BUK7109-75ATE

N-channel TrenchPLUS standard level FET

Rev. 02 — 10 February 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. The devices include TrenchPLUS diodes for ElectroStatic Discharge (ESD) protection and temperature sensing. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Allows responsive temperature monitoring due to integrated temperature sensor
- Electrostatically robust due to integrated protection diodes
- Low conduction losses due to low on-state resistance
- Q101 compliant
- Suitable for standard level gate drive sources

1.3 Applications

Electrical Power Assisted Steering (EPAS)

Variable Valve Timing for engines

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	-	75	V
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 7}}{\text{see } \frac{\text{Figure 8}}{\text{Figure 8}}}$	-	8	9	mΩ
S _{F(TSD)}	temperature sense diode temperature coefficient	I _F = 250 μA; T _j ≥ -55 °C; T _j ≤ 175 °C	-1.4	-1.54	-1.68	mV/K
V _{F(TSD)}	temperature sense diode forward voltage	$I_F = 250 \mu A; T_j = 25 \text{ °C}$	648	658	668	mV



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	Α	anode	mb	D A
3	D	drain		G A I A
4	K	cathode		(宏 平)
5	S	source	()()(3)()()	
mb	D	mounting base; connected to	1 2 4 5	s K
		drain	SOT426 (D2PAK)	mbl/317

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7109-75ATE	D2PAK	plastic single-ended surface-mounted package (D2PAK); 5 leads (one lead cropped)	SOT426

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Max 75 75 20 120 75 75 480 272 10 50 100	V V V A A A W mA V V
75 20 120 75 75 480 272 10	V V A A A A W mA
20 120 75 75 480 272 10 50	V A A A A W mA
120 75 75 480 272 10 50	A A A W mA
75 75 480 272 10 50	A A A W mA
75 480 272 10 50	A A W mA mA
480 272 10 50	A W mA mA
272 10 50	W mA mA
10 50	mA mA
50	mA
100	V
175	°C
175	°C
120	Α
75	Α
480	Α
739	mJ
6	kV
	175 120 75 480 739

^[1] Current is limited by power dissipation chip rating.

^[2] Continuous current is limited by package.

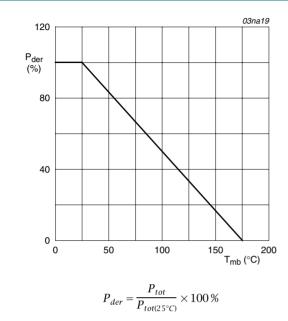


Fig 1. Normalized total power dissipation as a function of mounting base temperature

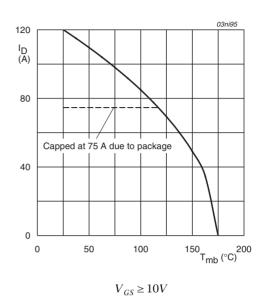
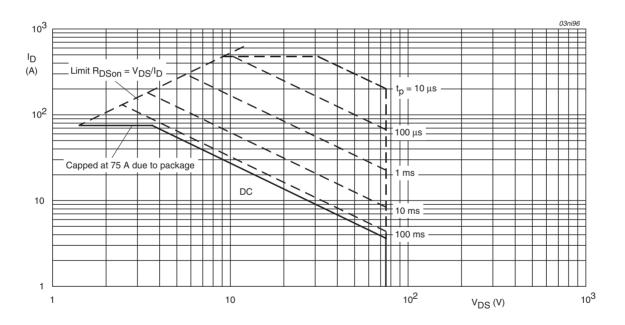


Fig 2. Continuous drain current as a function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	minimum footprint; mounted on a printed-circuit board	-	50	-	K/W
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 4	-	-	0.55	K/W

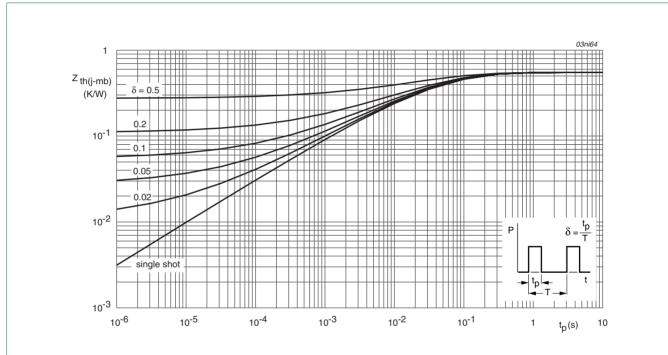


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

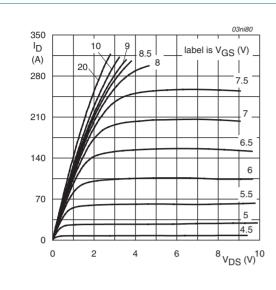
6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_i = 25 \text{ °C}$	75	-	-	V
	breakdown voltage	I _D = 0.25 mA; V _{GS} = 0 V; T _j = -55 °C	70	-	-	V
$V_{GS(th)}$	gate-source threshold $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ voltage see Figure 9		2	3	4	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 175 \text{ °C}$; see Figure 9	1	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 9	-	-	4.4	V
I _{DSS}	drain leakage current	$V_{DS} = 75 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.1	10	μΑ
		V _{DS} = 75 V; V _{GS} = 0 V; T _j = 175 °C	-	-	250	μΑ
$V_{(BR)GSS}$	gate-source breakdown voltage	$I_G = 1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j \ge -55 \text{ °C};$ $T_j \le 175 \text{ °C}$	20	22	-	V
		$I_G = -1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j \ge -55 \text{ °C};$ $T_j \le 175 \text{ °C}$	20	22	-	V
I _{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 25 \text{ °C}$	-	22	1000	nΑ
		$V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 25 \text{ °C}$	-	22	1000	nA
		V _{DS} = 0 V; V _{GS} = 10 V; T _j = 175 °C	-	-	10	μΑ
		$V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 175 ^{\circ}\text{C}$	-	-	10	μΑ
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 7; see Figure 8	-	8	9	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 7; see Figure 8	-	-	19	mΩ
$V_{F(TSD)}$	temperature sense diode forward voltage	$I_F = 250 \ \mu A; T_j = 25 \ ^{\circ}C$	648	658	668	mV
S _{F(TSD)}	temperature sense diode temperature coefficient	$I_F = 250 \ \mu A; T_j \ge -55 \ ^{\circ}C; T_j \le 175 \ ^{\circ}C$	-1.4	-1.54	-1.68	mV/k
$V_{F(TSD)hys}$	temperature sense diode forward voltage hysteresis	$I_F > 125 \mu A; I_F < 250 \mu A; T_j = 25 °C$	25	32	50	mV
Dynamic o	haracteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 60 \text{ V}; V_{GS} = 10 \text{ V};$	-	121	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 14</u>	-	20	-	nC
Q_{GD}	gate-drain charge		-	44	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	4700	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	800	-	pF
C _{rss}	reverse transfer capacitance		-	455	-	pF

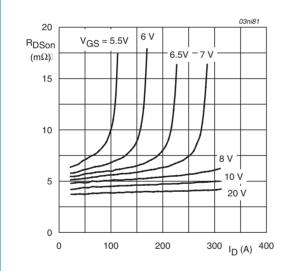
Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$t_{d(on)}$	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$ $R_{G(ext)} = 10 \Omega; T_j = 25 \text{ °C}$	-	35	-	ns
t _r	rise time		-	108	-	ns
t _{d(off)}	turn-off delay time		-	185	-	ns
t _f	fall time		-	100	-	ns
L _D	internal drain inductance	measured from upper edge of drain mounting base to centre of die; $T_j = 25$ °C	-	2.5	-	nΗ
L _S	internal source inductance	measured from source lead to source bond pad; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ
Source-dra	ain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 17</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = -10 \text{ V};$	-	75	-	ns
Q _r	recovered charge	$V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$	-	270	-	nC



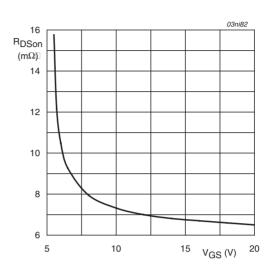
 $T_j = 25$ °C; $t_p = 300 \mu s$

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



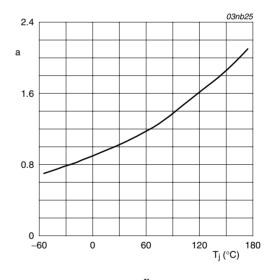
 $T_i = 25^{\circ}C; t_p = 300 \mu s$

Fig 7. Drain-source on-state resistance as a function of drain current; typical values



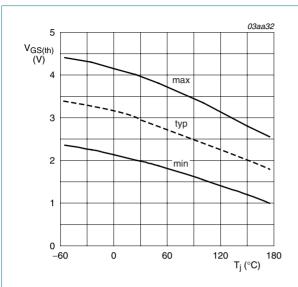
$$T_i = 25^{\circ}C; I_D = 50A$$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



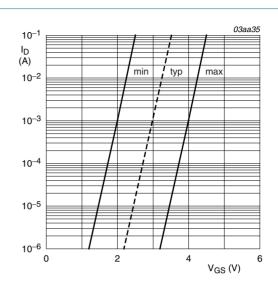
 $a = \frac{R_{DSon}}{R_{DSon(2.5^{\circ}C)}}$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



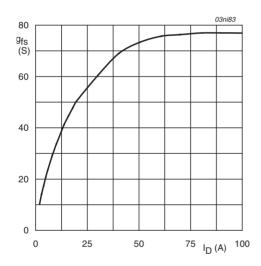
 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



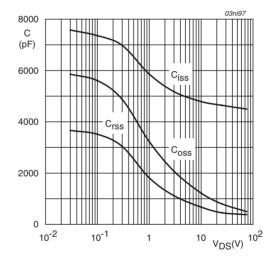
$$T_{j} = 25 \,^{\circ}C; V_{DS} = 5V$$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $T_i = 25^{\circ}C; V_{DS} = 25V$

Fig 11. Forward transconductance as a function of drain current; typical values



$$V_{GS} = 0V; f = 1MHz$$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

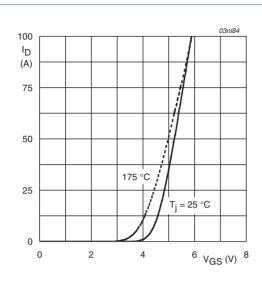


Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values

 $V_{DS} = 25V$

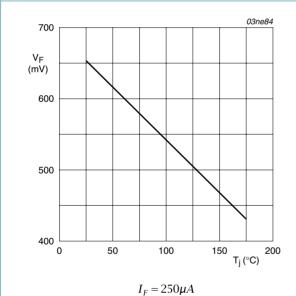
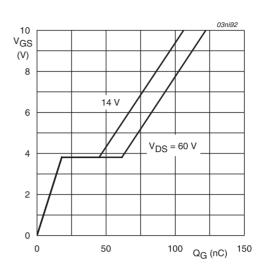
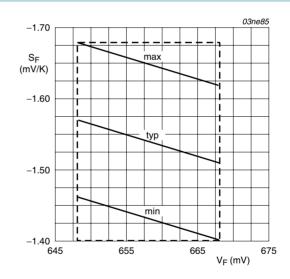


Fig 15. Forward transconductance as a function of drain current; typical values



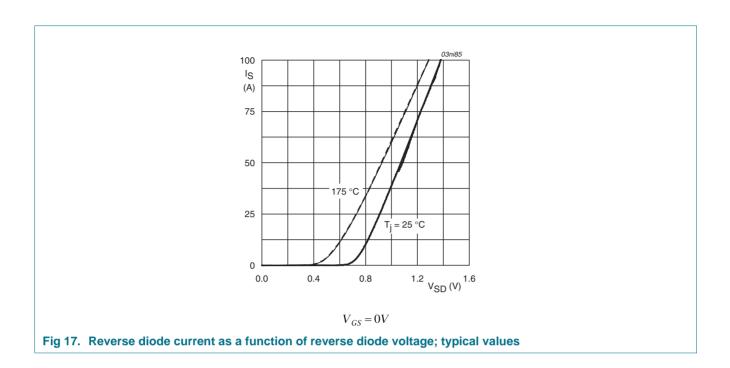
$$T_i = 25^{\circ}C; I_D = 25A$$

Fig 14. Gate-source voltage as a function of turn-on gate charge; typical values



$$V_F$$
 at $T_j = 25^{\circ}C$; $I_F = 250 \mu A$

Fig 16. Temperature coefficient of temperature sense diode as a function of forward voltage; typical values



7. Package outline

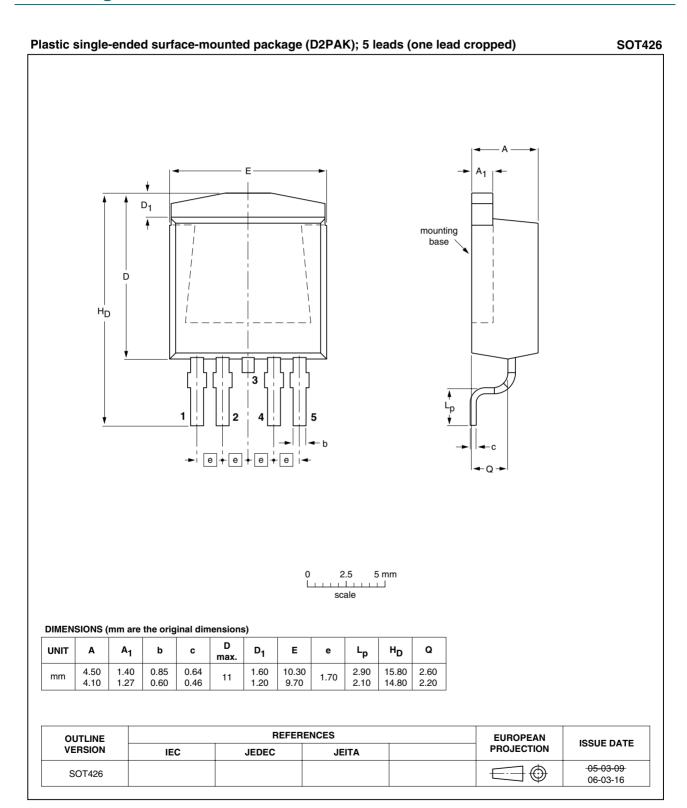


Fig 18. Package outline SOT426 (D2PAK)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
BUK7109-75ATE_2	20090210	Product data sheet	-	BUK71_7909_75ATE-01	
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 				
	 Legal texts 	have been adapted to the	new company name whe	re appropriate.	
	 Type numb 	er BUK7109-75ATE separ	ated from data sheet BUk	(71_7909_75ATE-01.	
BUK71_7909_75ATE-01 (9397 750 09878)	20020812	Product data sheet	-	-	

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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BUK7109-75ATE

N-channel TrenchPLUS standard level FET

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